


<b>Search Notes</b>  	<b>Application/Control No.</b>  10618154	<b>Applicant(s)/Patent Under Reexamination</b>  REICHARDT ET AL.
	<b>Examiner</b>  Hoang-Vu A Nguyen-Ba	<b>Art Unit</b>  2421

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
725/33-44, 112, 135-136, 139-140, 51, 61 -- text search only	3/5/08	HAN
Son Huynh consulted	3/5/08	HAN
EAST Text Search -- USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	10/17/08	HAN

INTERFERENCE SEARCH			
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